Surface and Interface Analysis
(*SIA. Surf. Interface Anal.*)

VOLUME 28 NUMBER 1 AUGUST 1999

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Abstracted/indexed by Analytical Abstracts (RSC), CAB Abstracts, Chemical Abstracts Service, Chemistry Citation Index, Current Contents/Physical, Chemical & Earth Sciences (ICI), Ei Page One, Ei COMPENDEX PLUS, Mass Spectrometry Bulletin (RSC), Reaction Citation Index, Research Alert (ISI), Science Citation Index (ISI), SciSearch, Materials Science Citation Index (ISI), Materials Information.

SIANDQ 28(1) 1–274 (1999)
ISSN 0142–2421

0142-2421(199908)28:1;1-S

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